Features

_	Double-conversion supernet architecture for high degree or image rejection
	FSK demodulation with phase-coincidence demodulator
	Low current consumption in active mode and very low standby current

Double conversion superbot architecture for high degree of image rejection

☐ Switchable LNA gain for improved dynamic range

☐ RSSI allows signal strength indication and ASK detection

☐ 32-pin Low profile Quad Flat Package (LQFP)

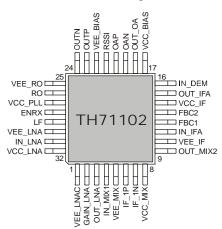
Ordering Information

Part Number	Temperature Code	Package Code	Delivery Form
TH71102	E (-40 °C to 85 °C)	NE (LQFP32)	250 pc/tray 2000 pc/T&R

Application Examples

- ☐ General digital data transmission
- ☐ Tire Pressure Monitoring Systems (TPMS)
- ☐ Remote Keyless Entry (RKE)
- Wireless access control
- Alarm and security systems
- Garage door openers
- □ Remote Controls
- Home and building automation
- □ Low-power telemetry systems

Pin Description



General Description

The TH71102 FSK/ASK double-conversion superheterodyne receiver IC is designed for applications in the European 433 MHz industrial-scientific-medical (ISM) band, according to the EN 300 220 telecommunications standard. It can also be used for any other system with carrier frequencies ranging from 260 MHz to 510 MHz (e.g. for applications according to FCC part 15 and ARIB STD-T67).





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1 Theory of Operation

1.1 General

With the TH71102 receiver chip, various circuit configurations can be arranged in order to meet a number of different customer requirements. For FSK reception the IF tank used in the phase coincidence demodulator can be constituted by an external ceramic discriminator. In ASK configuration, the RSSI signal is fed to an ASK detector, which is constituted by the operational amplifier.

The superheterodyne configuration is double conversion where MIX1 and MIX2 are driven by the internal local oscillator signals LO1 and LO2, respectively. This allows a high degree of image rejection, achieved in conjunction with an RF front-end filter. Efficient RF front-end filtering is realized by using a SAW, ceramic or helix filter in front of the LNA and by adding an LC filter at the LNA output.

A single-conversion variant, called TH71101, is also available. Both Receiver ICs have the same die. At the TH71101 the second mixer MIX2 operates as an amplifier.

The TH71102 receiver IC consists of the following building blocks:

- PLL synthesizer (PLL SYNTH) for generation of the first and second local oscillator signals LO1 and LO2, parts of the PLL SYNTH are: the high-frequency VCO1, the feedback dividers DIV_8 and DIV_2, a phase-frequency detector (PFD) with charge pump (CP) and a crystal-based reference oscillator (RO)
- Low-noise amplifier (LNA) for high-sensitivity RF signal reception
- First mixer (MIX1) for down-conversion of the RF signal to the first IF (IF1)
- Second mixer (MIX2) for down-conversion of the IF1 to the second IF (IF2)
- IF amplifier (IFA) to amplify and limit the IF2 signal and for RSSI generation
- Phase coincidence demodulator (DEMOD) with third mixer (MIX3) to demodulate the IF signal
- Operational amplifier (OA) for data slicing, filtering and ASK detection
- Bias circuitry for bandgap biasing and circuit shutdown

1.2 Technical Data Overview

Input frequency range: 260 MHz to 510 MHz	Range of IF2: 400 kHz to 22 MHz
Power supply range: 2.3 V to 5.5 V @ ASK	Maximum input level: -10 dBm @ ASK
Temperature range: -40 °C to +85 °C	0 dBm @ FSK
Standby current: 50 nA	Image rejection: > 65 dB (e.g. with 433.92 MHz
Operating current: 6.5 mA @ low gain mode	SAW front-end filter and at 10.7 MHz IF2)
8.2 mA @ high gain mode	Spurious emission: < -70 dBm
Sensitivity: -113 dBm @ ASK 1)	Input frequency acceptance range: up to ±100 kHz
-107 dBm @ FSK 2)	RSSI range: 70 dB
Maximum data rate: 260 kbps NRZ @ ASK	FSK deviation range: ±2.5 kHz to ±80 kHz
180 kbps NRZ @ FSK	Ğ
Range of IF1: 10 MHz to 80 MHz	

- 1) at 4 kbps NRZ, BER = 3.10^{-3} , 180 kHz IF filter BW, without SAW front-end-filter loss
- 2) at 4 kbps NRZ, BER = 3·10⁻³, ± 20 kHz FSK deviation, 180 kHz IF filter BW, without SAW front-end-filter loss



1.3 Block Diagram

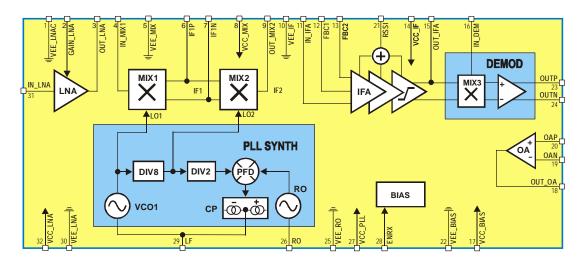


Fig. 1: TH71102 block diagram

1.4 Mode Configurations

ENRX	Mode	Description	
0	RX standby	RX disabled	
1	RX active	RX enable	

Note: ENRX are pulled down internally

1.5 LNA GAIN Control

V _{GAIN_LNA}	V _{GAIN_LNA} Mode Descrip		
< 0.8 V	HIGH GAIN	LNA set to high gain	
> 1.4 V	LOW GAIN	LNA set to low gain	

Note: hysteresis between gain modes to ensure stability

1.6 Frequency Planning

Frequency planning is straightforward for single-conversion applications because there is only one IF that can be chosen, and then the only possible choice is low-side or high-side injection of the LO signal (which is now the one and only LO signal in the receiver).

The receiver's double-conversion architecture requires careful frequency planning. Besides the desired RF input signal, there are a number of spurious signals that may cause an undesired response at the output. Among them are the image of the RF signal (that must be suppressed by the RF front-end filter), spurious signals injected to the first IF (IF1) and their images which could be mixed down to the same second IF (IF2) as the desired RF signal (they must be suppressed by the LC filter at IF1 and/or by low-crosstalk design).

By configuring the TH71102 for double conversion and using its internal PLL synthesizer with fixed feedback divider ratios of N1 = 8 (DIV_8) and N2 = 2 (DIV_2), four types of down-conversion are possible: low-side injection of LO1 and LO2 (**low-low**), LO1 low-side and LO2 high-side (**low-high**), LO1 high-side and LO2 low-side (**high-low**) or LO1 and LO2 high-side (**high-high**). The following table summarizes some equations that are useful to calculate the crystal reference frequency (REF), the first IF (IF1) and the VCO1 or first LO frequency (LO1), respectively, for a given RF and second IF (IF2).

Injection type	high-high	low-low	high-low	low-high
REF	(RF – IF2)/14	(RF – IF2)/18	(RF + IF2)/14	(RF + IF2)/18
LO1	16∙REF	16∙REF	16∙REF	16∙REF
IF1	LO1 – RF	RF – LO1	LO1 – RF	RF – LO1
LO2	2•REF	2•REF	2•REF	2•REF
IF2	LO2 – IF1	IF1 – LO2	IF1 – LO2	LO2 – IF1

1.6.1 Selected Frequency Plans

The following table depicts crystal, LO and image signals considering the examples of 315 MHz and 433.92 MHz RF reception at IF2 = 10.7 MHz. The columns in bold depict the selected frequency plans to receive at 315 MHz and 433.92 MHz, respectively.

Signal type	RF = 315 MHz	RF = 315 MHz	RF = 315 MHz	RF = 315 MHz	RF = 433.92 MHz	RF = 433.92 MHz	RF = 433.92 MHz	RF = 433.92 MHz
Injection type	high-high	low-low	high-low	low-high	high-high	low-low	high-low	low-high
REF / MHz	21.73571	16.90556	23.26429	18.09444	30.23000	23.51222	31.75857	24.70111
LO1 / MHz	347.77143	270.48889	372.22857	289.51111	483.68000	376.19556	508.13714	395.21778
IF1 / MHz	32.77143	44.51111	57.22857	25.48889	49.76000	57.72444	74.21714	38.70222
LO2 / MHz	43.47143	33.81111	46.52857	36.18889	60.46000	47.02444	63.51714	49.40222
RF image/MHz	380.54286	225.97778	429.45714	264.02222	533.44000	318.47112	582.35428	356.51556
IF1 image/MHz	54.17143	23.11111	35.82857	46.88889	71.16000	36.32444	52.81717	60.10222

1.6.2 Maximum Frequency Coverage

Parameter	f _{min}	f _{max}
Injection type	high-low	low-low
RF / MHz	251.8	516.95
REF / MHz	18.75	28.125
LO1 / MHz	300	450
IF1 / MHz	48.2	66.95
LO2 / MHz	37.5	56.25
IF2/ MHz	10.7	10.7

The selection of the reference crystal frequency is based on some assumptions. As for example: the first IF and the image frequencies should not be in a radio band where strong interfering signals might occur (because they could represent parasitic receiving signals), the LO1 signal should be in the range of 300 MHz to 450 MHz (because this is the optimum frequency range of the VCO1). Furthermore the first IF should be as high as possible to achieve highest RF image rejection.



2 Pin Definitions and Descriptions

Pin No.	Name	I/O Type	Functional Schematic	Description
3	OUT_LNA	analog output	VCC D 1.6V OUT_LNA VEE DVCC	LNA open-collector output, to be connected to external LC tank that resonates at RF
31	IN_LNA	analog input	IN_LNA VEE_LNAC	LNA input, approx. 26Ω single-ended
1	VEE_LNAC	ground	VEE 1	ground of LNA core (cascode)
2	GAIN_LNA	analog input	GAIN_LNA 400Ω	LNA gain control (input with hysteresis) RX standby: no pull-up
			VEE	RX active: pull-up
4	IN_MIX1	analog input	13Ω 1N_MIX1 4 VEE 13Ω 500μΑ	MIX1 input, approx. 33Ω single-ended
5	VEE_MIX	ground		ground of MIX1 and MIX2
6	IF1P	analog I/O	VCC	open-collector output, to be connected to external LC tank that resonates at first IF
7	IF1N	analog I/O		open-collector output, to be connected to external LC tank that resonates at first IF
8	VCC_MIX	supply		positive supply of MIX1 and MIX2
9	OUT_MIX2	analog output	OUT_MIX2 130Ω 230μA VEE	MIX2 output, approx. 330Ω output impedance
10	VEE_IF	ground		ground of IFA and DEMOD



Pin No.	Name	I/O Type	Functional Schematic	Description
11	IN_IFA	analog input	IN_IFA FBC1	IFA input, approx. 2.2kΩ input impedance
12	FBC1	analog I/O	11 VEE VCC II VEE 2.2k VEE VEE	to be connected to external IFA feedback capacitor
13	FBC2	analog I/O	FBC2 VEE	to be connected to external IFA feedback capacitor
14	VCC_IF	supply		positive supply of IFA and DEMOD
15	OUT_IFA	analog I/O	OUT_IFA VCC OUT_IFA VCE OUT_IF	IFA output and MIX3 input (of DEMOD)
16	IN_DEM	analog input	IN_DEM 47k	DEMOD input, to MIX3 core
17	VCC_BIAS	supply		positive supply of general bias system and OA
18	OUT_OA	analog output	OUT_OA 5000	OA output, 40uA current drive capability
19	OAN	analog input	OAN 50Ω OAP	negative OA input
20	OAP	analog input	19 VEE VEE 20	positive OA input



Pin No.	Name	I/O Type	Functional Schematic	Description
21	RSSI	analog output	RSSI 50Ω I (Pi) 21 36k	RSSI output, for RSSI and ASK detection, approx. 36kΩ output impedance
22	VEE_BIAS	ground		ground of general bias system and OA
23	OUTP	analog output	OUTP 50Ω	FSK positive output, output impedance of $100k\Omega$ to $300k\Omega$
24	OUTN	analog output	23 24 20µA 20µA	FSK negative output, output impedance of $100k\Omega$ to $300k\Omega$
25	VEE_RO	ground		ground of DIV, PFD, RO and charge pump
26	RO	analog input	7 VCC	RO input, Colpitts type oscillator with internal feedback capacitors
27	VCC_PLL	supply		positive supply of DIV, PFD, RO and charge pump
28	ENRX	digital input	ENRX 1.5k VCC VCC VCC VCC VCC VCC VCC VCC VCC VC	mode control input, CMOS-compatible with internal pull-down circuit
29	LF	analog I/O	29 VEE 400Ω VEE 4p	charge pump output and VCO1 control input
30	VEE_LNA	ground		ground of LNA biasing
32	VCC_LNA	supply		positive supply of LNA biasing



3 Technical Data

3.1 Absolute Maximum Ratings

Parameter	Symbol	Condition / Note	Min	Max	Unit	
Supply voltage	V_{CC}		0	7.0	V	
Input voltage	V _{IN}		- 0.3	V _{cc} +0.3	V	
Input RF level	P_{iRF}	@ LNA input		10	dBm	
Storage temperature	T _{STG}		-40	+125	°C	
Junction temperature	TJ			+150	°C	
Thermal Resistance	R_{thJA}			60	K/W	
Power dissipation	P _{diss}			0.1	W	
Electrostatic discharge	V _{ESD1}	human body model, 3)	-1.0	+1.0	I/\/	
Electrostatic discharge	V_{ESD2}	human body model, 4)	-0.75	+0.75	kV	

³⁾ all pins except OUT_LNA, IF1P and IF1N

3.2 Normal Operating Conditions

Parameter	Symbol	Condition	Min	Max	Unit
	$V_{CC,FSK}$	0 °C to 85 °C	2.5	5.5	
O and altern		-20 °C to 85 °C	2.6	5.5	
Supply voltage		-40 °C to 85 °C	2.7	5.5	V
	$V_{CC,ASK}$	-40 °C to 85 °C	2.3	5.5	
Operating temperature	T_A		-40	+85	٥C
Input low voltage (CMOS)	V _{IL}	ENRX pin		0.3*V _{CC}	V
Input high voltage (CMOS)	V_{IH}	ENRX pin	0.7*V _{CC}		V
Input frequency range	fi		251.8	516.95	MHz
First IF range	f _{IF1}		10	80	MHz
Second IF range	f _{IF2}		0.4	22	MHz
XOSC frequency	f _{ref}	set by the crystal	18.75	28.125	MHz
VCO frequency	f _{LO}	$f_{LO} = 16 \bullet f_{ref}$	300	450	MHz
Frequency deviation	Δf		±2.5	±80	kHz
FSK data rate	R _{FSK}	NRZ, C15 = NIP, 5)		180	kbps
ASK data rate	R _{ASK}	NRZ, C16 = NIP, 5)		260	kbps

⁵⁾ $B_{IF} = 400 \text{ kHz}, P_{IN} = -90 \text{ dBm}$

3.3 Crystal Parameters

Parameter Sym		Condition	Min	Max	Unit	
Crystal frequency	f ₀	fundamental mode, AT	18.75	28.125	MHz	
Load capacitance	CL		10	15	pF	
Static capacitance	C ₀			7	pF	
Series resistance	R ₁			50	Ω	

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⁴⁾ pin OUT_LNA, IF1P and IF1N



3.4 DC Characteristics

all parameters under normal operating conditions, unless otherwise stated; typical values at $T_A \! = 23~^{\circ}C$ and $V_{CC} \! = \! 3~V$

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Operating Currents						
Standby current	I _{SBY}	ENRX=0		50	100	nA
Supply current at low gain	I _{CC, low}	ENRX=1 GAIN_LNA=1	4.0	6.5	10.0	mA
Supply current at high gain	I _{CC, high}	ENRX=1 GAIN_LNA=0	4.5	8.2	12.0	mA
Digital Pin Characteristics						
Input low voltage CMOS	V _{IL}	ENRX pin	-0.3		0.3*V _{cc}	V
Input high voltage CMOS	V_{IH}	ENRX pin	0.7*V _{CC}		V _{CC} +0.3	V
Pull down current ENRX pin	I _{PDEN}	ENRX=1	0.1	2	10	μΑ
Low level input current ENRX pin	I _{INLEN}	ENRX=0			0.05	μΑ
Analog Pin Characteristics						
High level input current GAIN_LNA pin	I _{INHGAIN}	GAIN_LNA=1			0.05	μA
Pull up current GAIN_LNA pin active	I _{PUGAINa}	GAIN_LNA=0 ENRX=1	0.08	0.15	0.3	μA
Pull up current I _{PUGAINs} GAIN_LNA pin standby		GAIN_LNA=0 ENRX=0			0.05	μΑ
High gain input voltage	V _{IHGAIN}	ENRX=1			0.7	V
Low gain input voltage	V_{ILGAIN}	ENRX=1	1.5			V
Opamp Characteristics						
Opamp input offset voltage	$V_{\rm offs}$		-35		35	mV
Opamp input offset current	I _{offs}	I _{OAP} – I _{OAN}	-50		50	nA
Opamp input bias current	I _{bias}	0.5 * (I _{OAP} + I _{OAN})	-150		150	nA
RSSI Characteristics						
RSSI voltage at low input level	$V_{RSSI, low}$	P _i = -65 dBm, GAIN_LNA=1	0.5	1.0	1.5	V
RSSI voltage at high input level	V _{RSSI, high}	P _i = -35 dBm, GAIN_LNA=1	1.2	1.9	2.5	V



AC System Characteristics 3.5

all parameters under normal operating conditions, unless otherwise stated; typical values at T_A = 23 °C and V_{CC} = 3 V, RF at 433.92 MHz; SAW frond-end filter loss and IF at 10.7 MHz;

all parameters based on test circuits as shown in Fig. 2, Fig.3 and Fig. 5

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Receive Characteristics				•		
Input sensitivity – FSK (standard)	P _{min, ST}	$B_{IF} = 180 \text{kHz},$ $\Delta f = \pm 20 \text{kHz},$ 4 kbps NRZ, $BER \le 3.10^{-3}, 6)$		-104		dBm
Input sensitivity – FSK (narrow band)	P _{min, NB}	$B_{IF} = 30kHz,$ $\Delta f = \pm 5kHz,$ 4kbps NRZ, $BER \le 3 \cdot 10^{-3}, 6)$		-108		dBm
Input sensitivity – ASK	P _{min, ASK}	$B_{IF} = 180 \text{kHz},$ 4kbps NRZ, BER $\leq 3.10^{-3}$, 6)		-110		dBm
Maximum input signal – FSK	P _{max, FSK}	BER ≤ 3·10 ⁻³ GAIN_LNA = 1		0		dBm
Maximum input signal – ASK	P _{max, ASK}	BER ≤ 3·10 ⁻³ GAIN_LNA = 1		-10		dBm
Spurious emission	P _{spur}				-70	dBm
Image rejection	ΔP_{imag}			65		dB
Start-up Parameters		·				
Crystal start-up time	T _{XTL}	ENRX from 0 to 1			0.9	ms
Receiver start-up time	T _{RX}	ENRX from 0 to 1, depends on data slicer time constant, valid data at output			T _{XTL} + R4 · C17	
PLL Parameters						
VCO gain	K _{VCO}			250		MHz/V
Charge pump current	I _{CP}			60		μΑ

⁶⁾ incl. 3 dB loss of front-end SAW filter



4 Test Circuits

4.1 Standard FSK Reception

4.1.1 Standard FSK Application Circuit

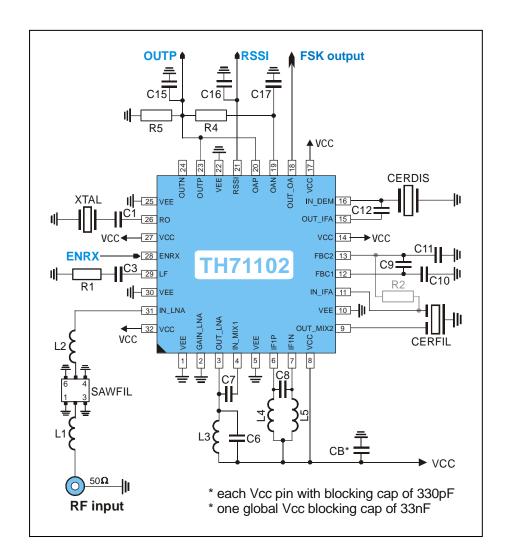


Fig. 2: Test circuit for FSK reception

Circuit Features

- Tolerates input frequency variations
- · Well-suited for NRZ, Manchester and similar codes

4.1.2 Standard FSK Component List

Part	Size	Value @ 433.92 MHz	Tolerance	Description
C1	0805	27 pF	±5%	crystal series capacitor
C3	0603	1 nF	±10%	loop filter capacitor
C6	0603	4.7 pF	±5%	LNA output tank capacitor
C7	0603	2.2 pF	±5%	MIX1 input matching capacitor
C8	0603	27 pF	±5%	IF1 tank capacitor
C9	0603	33 nF	±10%	IFA feedback capacitor
C10	0603	1 nF	±10%	IFA feedback capacitor
C11	0603	1 nF	±10%	IFA feedback capacitor
C12	0805	10 pF	±5%	DEMOD phase-shift capacitor
C15	0805	100 pF	±5%	demodulator output low-pass capacitor, this value for data rates < 20 kbps NRZ
C16	0805	1.5 nF	±10%	RSSI output low-pass capacitor
C17	0805	10 nF	±10%	data slicer capacitor, this value for data rates > 0.8 kbps NRZ
R1	0603	10 kΩ	±5%	loop filter resistor
R2	0603	330 Ω	±5%	optional CERFIL output matching resistor
R4	0805	330 kΩ	±5%	data slicer resistor
R5	0805	220 kΩ	±5%	loading resistor
L1	0603	68 nH	±5%	SAW filter matching inductor from Würth-Elektronik
L2	0603	82 nH	±5%	(WE-KI series), or equivalent part
L3	0603	15 nH	±5%	LNA output tank inductor from Würth-Elektronik (WE-KI series), or equivalent part
L4	0805	100 nH	±5%	IF1 tank inductor from Würth-Elektronik (WE-KI series)
L5	0805	100 nH	±5%	or equivalent part
XTAL	SMD 6x3.5	23.51222 MHz @ RF = 433.92 MHz	±25ppm cal. ±30ppm temp.	fundamental-mode crystal from Telcona/Horizon or equivalent part
SAWFIL	SMD 3x3	SAFCC433MBL0X00 (f ₀ = 433.92 MHz)	$B_{3dB} = 840 \text{ kHz}$	low-loss SAW filter from Murata, or equivalent part
CERFIL	SMD 3.45x3.1	SFECF10M7HA00	$B_{3dB} = 180 \text{ kHz}$	ceramic filter from Murata, or equivalent part
CERDIS	SMD 4.5x2	CDSCB10M7GA135		ceramic discriminator from Murata, or equivalent part

• For component values for other frequencies, please refer to the EVB descriptions



4.2 Narrow Band FSK Reception

4.2.1 Narrow Band FSK Application Circuit

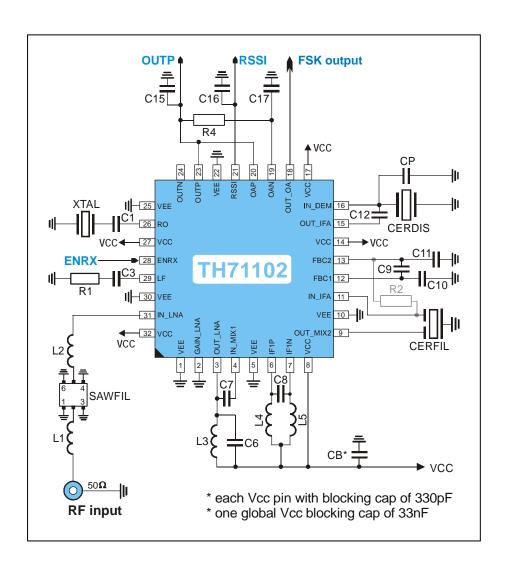


Fig. 3: Test circuit for FSK reception (narrow band)

Circuit Features

Applicable for narrow band FSK

4.2.2 Narrow Band FSK Component List

Part	Size	Value @ 433.92 MHz	Tolerance	Description
C1	0805	27 pF	±5%	crystal series capacitor
C3	0603	1 nF	±10%	loop filter capacitor
C6	0603	4.7 pF	±5%	LNA output tank capacitor
C7	0603	2.2 pF	±5%	MIX1 input matching capacitor
C8	0603	27 pF	±5%	IF1 tank capacitor
C9	0603	33 nF	±10%	IFA feedback capacitor
C10	0603	1 nF	±10%	IFA feedback capacitor
C11	0603	1 nF	±10%	IFA feedback capacitor
C12	0805	1.5 pF	±5%	DEMOD phase-shift capacitor
C15	0805	220 pF	±5%	demodulator output low-pass capacitor, this value for data rates < 10 kbps NRZ
C16	0805	1.5 nF	±10%	RSSI output low-pass capacitor
C17	0805	10 nF	±10%	data slicer capacitor, this value for data rates > 0.8 kbps NRZ
CP	0603	6.8 - 8.2 pF	±5%	ceramic resonator loading capacitor
R1	0603	10 kΩ	±5%	loop filter resistor
R2	0805	330 Ω	±5%	optional CERFIL output matching resistor
R4	0805	330 kΩ	±5%	data slicer resistor
L1	0603	68 nH	±5%	SAW filter matching inductor from Würth-Elektronik
L2	0603	82 nH	±5%	(WE-KI series), or equivalent part
L3	0603	15 nH	±5%	LNA output tank inductor from Würth-Elektronik (WE-KI series), or equivalent part
L4	0805	100 nH	±5%	IF1 tank inductor from Würth-Elektronik (WE-KI series)
L5	0805	100 nH	±5%	or equivalent part
XTAL	SMD 6x3.5	23.51222 MHz @ RF = 433.92 MHz	±25ppm cal. ±30ppm temp.	fundamental-mode crystal from Telcona/Horizon or equivalent part
SAWFIL	SMD 3x3	SAFCC433MBL0X00 (f ₀ = 433.92 MHz)	$B_{3dB} = 840 \text{ kHz}$	low-loss SAW filter from Murata, or equivalent part
CERFIL	Leaded	SFKLA10M7NL00	$B_{3dB} = 30 \text{ kHz}$	ceramic filter from Murata, or equivalent part
OLIVIT	type	SFVLA10M7LF00	$B_{3dB} = 80 \text{ kHz}$	optional, ceramic filter from Murata, or equivalent part
CERDIS	SMD 4.5x2	CDSCB10M7GA135		ceramic discriminator from Murata, or equivalent part

• For component values for other frequencies, please refer to the EVB descriptions



4.3 ASK Reception

4.3.1 ASK Application Circuit

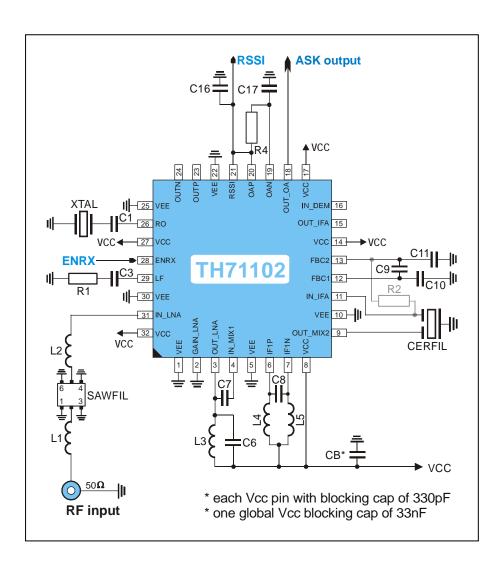


Fig. 5: Test circuit for ASK reception

4.3.2 ASK Component List

Part	Size	Value @ 433.92 MHz	Tolerance	Description
C1	0805	27 pF	±5%	crystal series capacitor
C3	0603	1 nF	±10%	loop filter capacitor
C6	0603	4.7 pF	±5%	LNA output tank capacitor
C7	0603	2.2 pF	±5%	MIX1 input matching capacitor
C8	0603	27 pF	±5%	IF1 tank capacitor
C9	0603	33 nF	±10%	IFA feedback capacitor
C10	0603	1 nF	±10%	IFA feedback capacitor
C11	0603	1 nF	±10%	IFA feedback capacitor
C16	0805	1.5 nF	±10%	RSSI output low-pass capacitor, this value for data rates < 10 kbps NRZ
C17	0805	10 nF	±10%	data slicer capacitor, this value for data rates > 0.8 kbps NRZ
R1	0603	10 kΩ	±5%	loop filter resistor
R2	0603	330 Ω	±5%	optional CERFIL output matching resistor
R4	0805	330 kΩ	±5%	data slicer resistor
L1	0603	68 nH	±5%	SAW filter matching inductor from Würth-Elektronik
L2	0603	82 nH	±5%	(WE-KI series), or equivalent part
L3	0603	15 nH	±5%	LNA output tank inductor from Würth-Elektronik (WE-KI series), or equivalent part
L4	0805	100 nH	±5%	IF1 tank inductor from Würth-Elektronik (WE-KI series)
L5	0805	100 nH	±5%	or equivalent part
XTAL	SMD 6x3.5	23.51222 MHz @ RF = 433.92 MHz	±25ppm cal. ±30ppm temp.	fundamental-mode crystal from Telcona/Horizon or equivalent part
SAWFIL	SMD 3x3	SAFCC433MBL0X00 (f ₀ = 433.92 MHz)	$B_{3dB} = 840 \text{ kHz}$	low-loss SAW filter from Murata, or equivalent part
CERFIL	SMD 3.45x3.1	SFECF10M7HA00	$B_{3dB} = 180 \text{ kHz}$	ceramic filter from Murata, or equivalent part
OLIVITE	Leaded type	SFVLA10M7LF00	$B_{3dB} = 80 \text{ kHz}$	optional, ceramic filter from Murata, or equivalent part

• For component values for other frequencies, please refer to the EVB descriptions



5 Package Description



The device TH71102 is RoHS compliant.

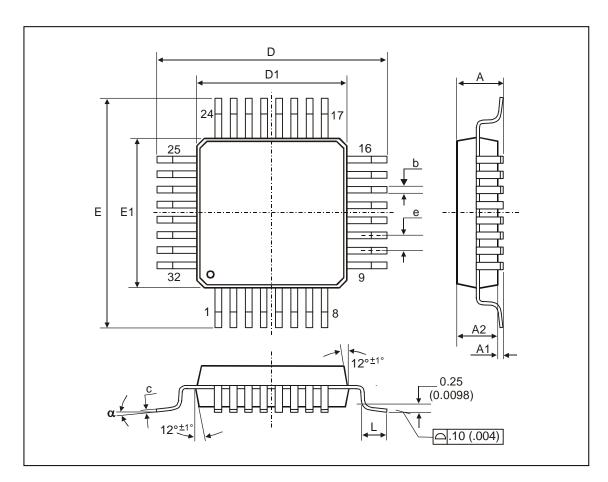


Fig. 6: LQFP32 (Low profile Quad Flat Package)

All Dim	All Dimension in mm, coplanaríty < 0.1mm										
	E1, D1	E, D	Α	A1	A2	е	b	С	L	α	
min	7.00	9.00	1.40	0.05	1.35	0.8	0.30	0.09	0.45	0°	
max	7.00	9.00	1.60	0.15	1.45	0.0	0.45	0.20	0.75	7°	
All Dim	All Dimension in inch, coplanaríty < 0.004"										
min	0.276	0.354	0.055	0.002	0.053	0.031	0.012	0.0035	0.018	0°	
max	0.270	0.004	0.063	0.006	0.057	0.031	0.018	0.0079	0.030	7°	

5.1 Soldering Information

 The device TH71102 is qualified for MSL3 with soldering peak temperature 260 deg C according to JEDEC J-STD-20

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6 Reliability Information

This Melexis device is classified and qualified regarding soldering technology, solderability and moisture sensitivity level, as defined in this specification, according to following test methods:

Reflow Soldering SMD's (Surface Mount Devices)

IPC/JEDEC J-STD-020
 "Moisture/Reflow Sensitivity Classification for Nonhermetic Solid State Surface Mount Devices (classification reflow profiles according to table 5-2)"

Wave Soldering SMD's (Surface Mount Devices)

 EN60749-20 "Resistance of plastic- encapsulated SMD's to combined effect of moisture and soldering heat"

Solderability SMD's (Surface Mount Devices)

 EIA/JEDEC JESD22-B102 "Solderability"

For all soldering technologies deviating from above mentioned standard conditions (regarding peak temperature, temperature gradient, temperature profile etc) additional classification and qualification tests have to be agreed upon with Melexis.

The application of Wave Soldering for SMD's is allowed only after consulting Melexis regarding assurance of adhesive strength between device and board.

7 ESD Precautions

Electronic semiconductor products are sensitive to Electro Static Discharge (ESD).

Always observe Electro Static Discharge control procedures whenever handling semiconductor products.



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